



**Model No. LDLC-442-XFYP  
LONG COHERENCE 442nm DIODE LASER UP TO >30mW**

The LDLC-series 442 nm diode laser is constructed with features of long coherent length >1m, stable wavelength, long lifetime and easy operating. It is widely used in holography, interference, fluorescence, photoetching, flow cytometry, DNA sequencing, Raman spectroscopy, laser radar, precision measurement, and many other applications. Housed in ultra-compact package, this laser is the ideal choice for OEM instrumentation, systems design and integration, and for end user applications in research and development.

**SPECIFICATIONS**

<b>Model No.</b>	<b>LDLC-442-XFYP</b>
<b>Wavelength (nm)</b>	442±0.5
<b>Output power (mW)</b>	>30 ( <b>X=30</b> )
<b>Transverse mode</b>	Multimode
<b>Operating mode</b>	CW
<b>Power stability (rms, over 4 hours)</b>	<1% ( <b>P=D</b> )
<b>Coherent length (m)</b>	>1
<b>Beam diameter at aperture (1/e<sup>2</sup>, mm)</b>	~2.5x1.0
<b>Beam divergence, full angle (mrad)</b>	~0.5x4.0
<b>Polarization ratio</b>	>50:1, Horizontal ±5 degree
<b>Warm-up time (minutes)</b>	<5
<b>Beam height from base plate (mm)</b>	30
<b>Operating temperature (°C)</b>	20~30
<b>Laser head</b>	122.5(L) x65(W) x50(H) mm <sup>3</sup> , 1.0 kg
<b>Power supply (90-260VAC)</b>	<b>Elite Power Supply (Y=E):</b> 171(L) x130(W) x62.2(H) mm <sup>3</sup> , 1.2 kg; complete FDA compliant features (turnkey switch and interlock); easy to operate; CW mode
<b>Expected lifetime (hours)</b>	10,000
<b>Warranty</b>	10 months
<b>Remarks</b>	The stability of output power may change when you adjust the output power. For example, the stability of output power at the maximum output power is <10%, the stability may change to >10% when you adjust the output power down.

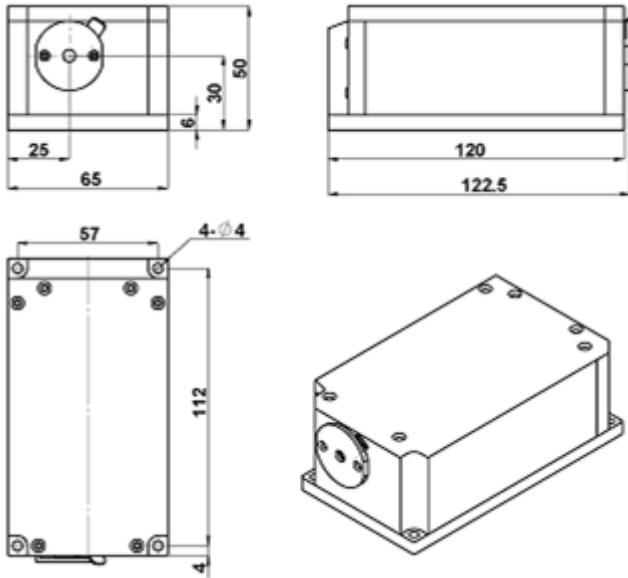
**Note: The above specifications are subject to change without notice.**



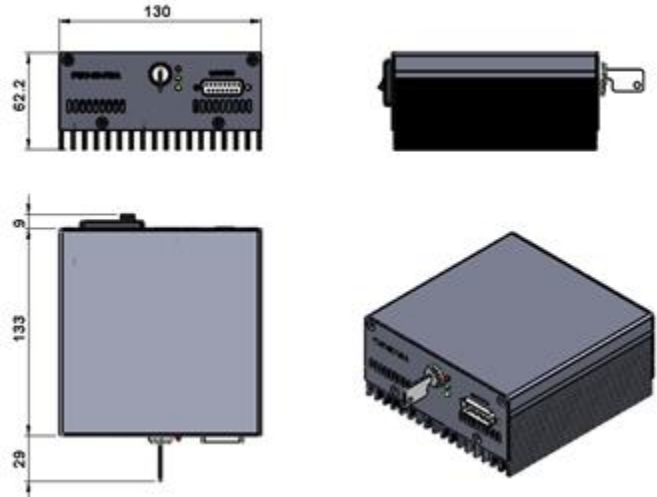


MECHANICAL OUTLINE (unit: mm)

*Laser Head*

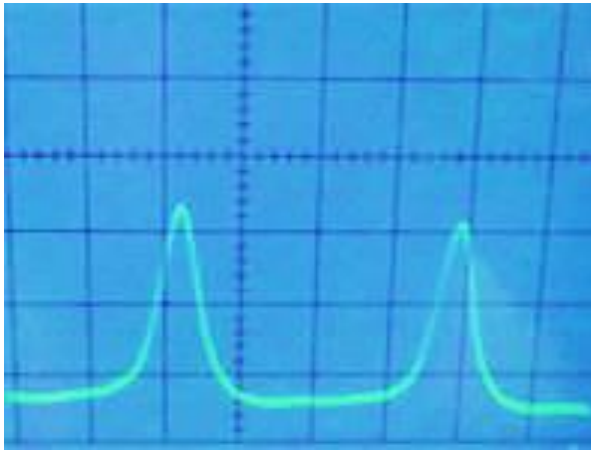


*Elite Power Supply (Y=E)*

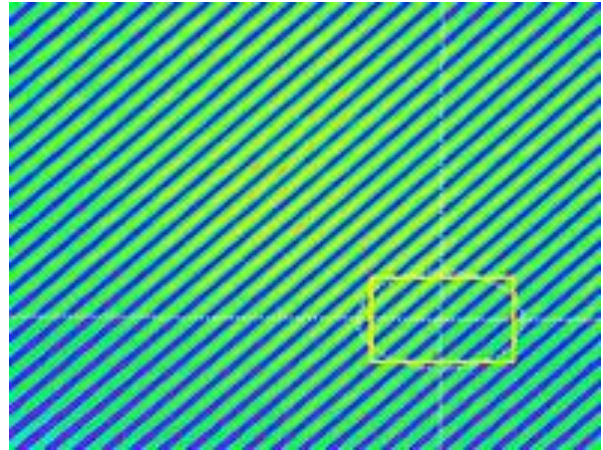


TESTING RESULTS OF LDLC-442-XFYP

*Longitudinal Mode Testing*



*Coherent Fringes Testing at 1m*



Note: The above specifications are subject to change without notice.

